SCAS005B - JULY 1987 - REVISED APRIL 1993

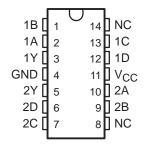
- Flow-Through Architecture Optimizes **PCB Layout**
- Center-Pin V<sub>CC</sub> and GND Configurations **Minimize High-Speed Switching Noise**
- EPIC™ (Enhanced-Performance Implanted) CMOS) 1-µm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic Small-Outline Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs

### description

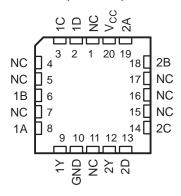
These devices contain two independent 4-input AND gates. They perform the Boolean functions  $Y = A \bullet B \bullet C \bullet D$  or  $Y = \overline{A} + \overline{B} + \overline{C} + \overline{D}$  in positive logic.

The 54AC11021 is characterized for operation over the full military temperature range of -55°C to 125°C. The 74AC11021 is characterized for operation from -40°C to 85°C.

#### **54AC11021...J PACKAGE 74AC11021...D OR N PACKAGE** (TOP VIEW)



#### **54AC11021...FK PACKAGE** (TOP VIEW)



NC - No internal connection

#### **FUNCTION TABLE** (each gate)

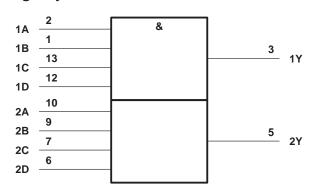
	OUTPUT			
Α	В	С	D	Y
Н	Н	Н	Н	Н
L	X	X	X	L
Χ	L	Χ	X	L
Χ	Χ	L	X	L
Х	Χ	Χ	L	L

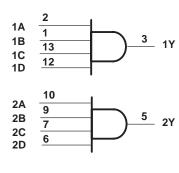
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### logic symbol†

# logic diagram (positive logic)





Pin numbers shown are for the D, J, and N packages.

## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V <sub>CC</sub>	$-0.5\ V$ to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)	$\dots$ -0.5 V to V <sub>CC</sub> + 0.5 V
Output voltage range, V <sub>O</sub> (see Note 1)	$\dots$ -0.5 V to V <sub>CC</sub> + 0.5 V
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ )	±20 mA
Output clamp current, $I_{OK}$ ( $V_O < 0$ or $V_O > V_{CC}$ )	±50 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$	±50 mA
Continuous current through V <sub>CC</sub> or GND	±100 mA
Storage temperature range	65°C to 150°C

<sup>‡</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

### recommended operating conditions

			54	1AC1102	AC11021 74AC11021			LINIT	
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage		3	5	5.5	3	5	5.5	V
		V <sub>CC</sub> = 3 V	2.1			2.1			
$V_{IH}$	High-level input voltage	V <sub>CC</sub> = 4.5 V	3.15			3.15			V
		V <sub>CC</sub> = 5.5 V	3.85			3.85			
V <sub>IL</sub>		VCC = 3 V			0.9			0.9	
	Low-level input voltage	V <sub>CC</sub> = 4.5 V			1.35			1.35	V
		V <sub>CC</sub> = 5.5 V			1.65			1.65	
٧ <sub>I</sub>	Input voltage		0		Vcc	0		Vcc	V
٧o	Output voltage		0		Vcc	0		Vcc	V
		V <sub>CC</sub> = 3 V			-4			-4	
loH	High-level output current	V <sub>CC</sub> = 4.5 V			-24			-24	mA
		V <sub>CC</sub> = 5.5 V			-24			-24	
		V <sub>CC</sub> = 3 V			12			12	
lOL	Low-level output current	V <sub>CC</sub> = 4.5 V		•	24			24	mA
		V <sub>CC</sub> = 5.5 V			24			24	
Δt/Δν	Input transition rise or fall rate		0		10	0		10	ns/V
TA	Operating free-air temperature		-55		125	-40		85	°C

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	TEST COMPLTIONS	V	T	λ = 25°C	;	54AC1	11021	74AC1	1021		
PARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
		3 V	2.9			2.9		2.9			
	ΙΟΗ = – 50 μΑ	4.5 V	4.4			4.4		4.4			
		5.5 V	5.4			5.4		5.4			
Vou	$I_{OH} = -4 \text{ mA}$	3 V	2.58			2.4		2.48		V	
VOH	04.54	4.5 V	3.94			3.7		3.8		V	
	$I_{OH} = -24 \text{ mA}$	5.5 V	4.94			4.7		4.8			
	$I_{OH} = -50 \text{ mA}^{\dagger}$	5.5 V				3.85					
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V						3.85			
	I <sub>OL</sub> = 50 μA	3 V			0.1		0.1		0.1		
		4.5 V			0.1		0.1		0.1		
		5.5 V			0.1		0.1		0.1		
V/01	I <sub>OL</sub> = 12 mA	3 V			0.36		0.5		0.44	V	
VOL	I <sub>OL</sub> = 24 mA	4.5 V			0.36		0.5		0.44	ľ	
	10L = 24 IIIA	5.5 V			0.36		0.5		0.44		
	$I_{OL} = 50 \text{ mA}^{\dagger}$	5.5 V					1.65				
	$I_{OL} = 75 \text{ mA}^{\dagger}$	5.5 V							1.65		
lį	V <sub>I</sub> = V <sub>CC</sub> or GND	5.5 V			±0.1		±1	·	±1	μΑ	
Icc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			4		80		40	μΑ	
Ci	V <sub>I</sub> = V <sub>CC</sub> or GND	5 V		3.5						pF	

<sup>†</sup> Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

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# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 3.3 V $\pm$ 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T,	<sub>Δ</sub> = 25°C	;	54AC1	11021	74AC1	1021	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
t <sub>PLH</sub>	Any	V	1.5	8.2	11.4	1.5	13.9	1.5	13	no
t <sub>PHL</sub>	Any	1	1.5	6.4	8.7	1.5	9.9	1.5	9.3	ns

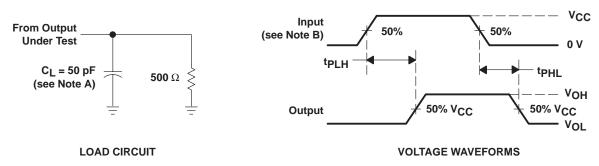
# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 5 V $\pm$ 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T,	գ = 25°C	;	54AC1	1021	74AC1	11021	UNIT
FARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
t <sub>PLH</sub>	Anv	Y	1.5	5.6	7.8	1.5	9.4	1.5	8.8	no
<sup>t</sup> PHL	Any		1.5	4.6	6.5	1.5	7.4	1.5	6.9	ns

# operating characteristics, V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C

PARAMETER		TEST CONDITIONS	TYP	UNIT
C <sub>pd</sub>	Power dissipation capacitance per gate	$C_L = 50 \text{ pF},  f = 1 \text{ MHz}$	38	pF

#### PARAMETER MEASUREMENT INFORMATION



NOTES: A.  $C_L$  includes probe and jig capacitance.

- B. Input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_O = 50 \Omega$ ,  $t_f = 3 \text{ ns}$ ,  $t_f = 3 \text{ ns}$ .
- C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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